

Valley lifetimes in monolayer WSe₂ from time-resolved Kerr-rotation measurements

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Two-dimensional transition metal dichalcogenides (TMDs) offer the possibility to address the electron's valley degree of freedom making them interesting for valley-based electronics, so-called valleytronics. We report on nanosecond long, gate-dependent valley lifetimes of free charge carriers in WSe₂, unambiguously identified by the combination of time-resolved Kerr rotation (TRKR), Photoluminescence (Fig. 1a) and electrical transport measurements. While the valley polarization increases, black data points in Fig. 1b for $U_{BG} > 0$, when tuning the Fermi level into the conduction (Fig 1b) or valence band, there is a strong decrease of the respective valley lifetimes, black data points Fig. 1c, consistent with both electron-phonon and spin-orbit scattering. The longest lifetimes are seen for spin-polarized bound excitons in the band gap region, red data points in Fig. 1c. We explain our findings via two distinct, Fermi level-dependent scattering channels of optically excited, valley polarized bright trions either via dark or bound states. By electrostatic gating we demonstrate that WSe₂ can be tuned to be either an ideal host for long-lived localized spin states or allow for nanosecond valley lifetimes of free charge carriers (>10 ns) explaining the huge variation in previously reported lifetimes extracted from TRKR [1],[2],[3]

References

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Figures

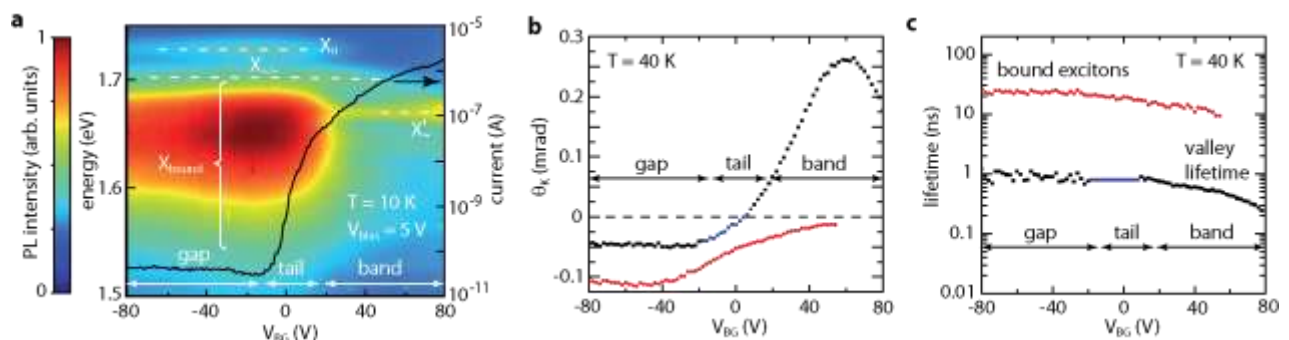


Figure 1: a) Gate-dependent photoluminescence and electrical transport measurements are used to determine the position of the Fermi level within the band structure of the TMD as a function of gate-voltage. b) Gate-dependent Kerr rotation amplitudes θ_K and c) lifetimes.